2023 Austrochip Workshop on Microelectronics (Austrochip 2023)

Graz, Austria 20 – 21 September 2023



IEEE Catalog Number: CFP23AUS-POD ISBN: 979-8-3503-5786-8

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 IEEE Catalog Number:
 CFP23AUS-POD

 ISBN (Print-On-Demand):
 979-8-3503-5786-8

 ISBN (Online):
 979-8-3503-5785-1

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